

DTP10N60SJ-VB Datasheet

N-Channel 600V (D-S)Super Junction Power MOSFET

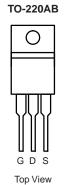
PRODUCT SUMMARY					
V _{DS} (V) at T _J max.	600				
R _{DS(on)} at 25 °C (Ω)	V _{GS} = 10 V 0.47				
Q _g max. (nC)	35				
Q _{gs} (nC)	3				
Q _{gd} (nC)	3.7				
Configuration	Single				

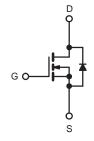
FEATURES

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V_{DS}	600	V		
Gate-Source Voltage			V_{GS}	± 30	V	
Continuous Drain Current (T _{.I} = 150 °C)	\/ at 10 \/	10 V $\frac{T_C = 25 \text{ °C}}{T_C = 100 \text{ °C}}$ I_D	10			
Continuous Drain Current (1) = 150 °C)	V _{GS} at 10 V		ıD	6.1	Α	
Pulsed Drain Current ^a			I _{DM}	30		
Linear Derating Factor				1.62/1.3/0.2	W/°C	
Single Pulse Avalanche Energy b			E _{AS}	121	mJ	
Maximum Power Dissipation			P _D	83/83/31	W	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +150	°C		
Drain-Source Voltage Slope T _J = 125 °C		dV/dt 50 3.1	50	V/ns		
Reverse Diode dV/dt ^d			3.1	V/IIS		
Soldering Recommendations (Peak Temperature) c for 10 s			304	°C		

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b. $V_{DD}=50$ V, starting $T_J=25$ °C, L=28.2 mH, $R_g=25$ Ω , $I_{AS}=4.5$ A. c. 1.6 mm from case.
- d. $I_{SD} \le I_D$, dI/dt = 100 A/ μ s, starting $T_J = 25$ °C.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	82	°C/W	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.7	G/ VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				-			
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 250 μA	600	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2	-	4	V
			V _{GS} = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	I_{GSS}		V _{GS} = ± 30 V	-	-	± 1	μA
			= 600 V, V _{GS} = 0 V	-	-	1	
Zero Gate Voltage Drain Current	I_{DSS}		/, V _{GS} = 0 V, T _J = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V		-	0.47	-	Ω
Forward Transconductance	9fs	V _{DS}	s = 30 V, I _D = 5 A	-	16	-	S
Dynamic		•					
Input Capacitance	C _{iss}		Voc = 0 V	-	680	-	
Output Capacitance	Coss	1	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$ f = 1 MHz		140	-	pF
Reverse Transfer Capacitance	C _{rss}	7			5	-	
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	- V _{DS} = 0 V to 520 V, V _{GS} = 0 V		-	63	-	
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	113	-	
Total Gate Charge	Qg			-	38	56	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 5 \text{ A}, V_{DS} = 520 \text{ V}$		-	4	-	nC
Gate-Drain Charge	Q _{gd}			-	4.5	-	1
Turn-On Delay Time	t _{d(on)}			-	13	25	
Rise Time	t _r	$V_{DD} = 520 \text{ V, } I_D = 5 \text{ A,}$		-	11	35	1
Turn-Off Delay Time	t _{d(off)}		= 10 V, $R_g = 9.1 \Omega$	-	81	90	ns ns
Fall Time	t _f			-	25	40	
Gate Input Resistance	R_g	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	10	
Pulsed Diode Forward Current	I _{SM}			-	-	30	A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 5 A, V _{GS} = 0 V		-	-	1.5	V
Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = I _S = 5 A, dl/dt = 100 A/μs, V _R = 400 V		-	270	-	ns
Reverse Recovery Charge	Q _{rr}			-	3.3	-	μC
Reverse Recovery Current	I _{RRM}			_	30		Α

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

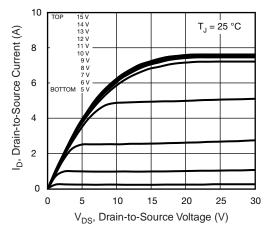


Fig. 1 - Typical Output Characteristics

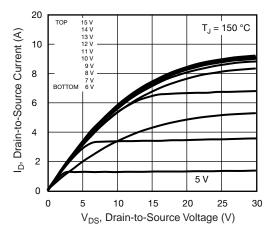


Fig. 2 - Typical Output Characteristics

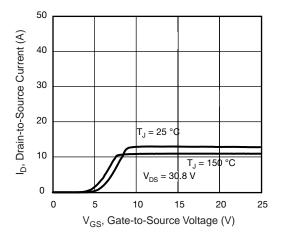


Fig. 3 - Typical Transfer Characteristics

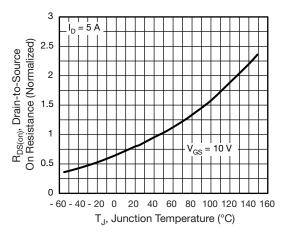


Fig. 4 - Normalized On-Resistance vs. Temperature

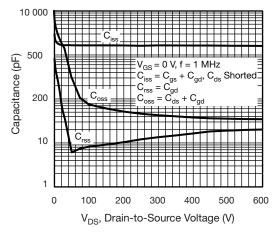


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

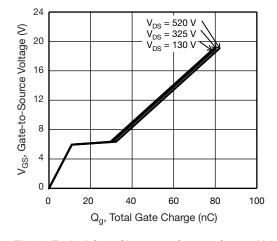


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

3



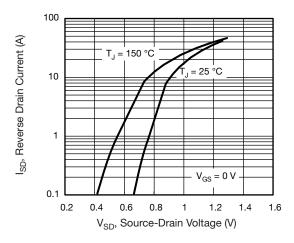


Fig. 7 - Typical Source-Drain Diode Forward Voltage

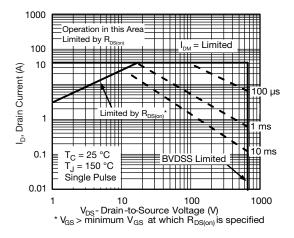


Fig. 8 - Maximum Safe Operating Area

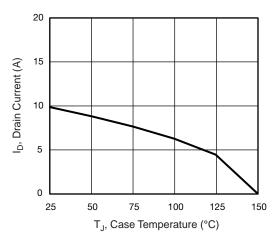


Fig. 9 - Maximum Drain Current vs. Case Temperature

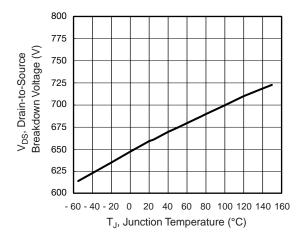


Fig. 10 - Temperature vs. Drain-to-Source Voltage

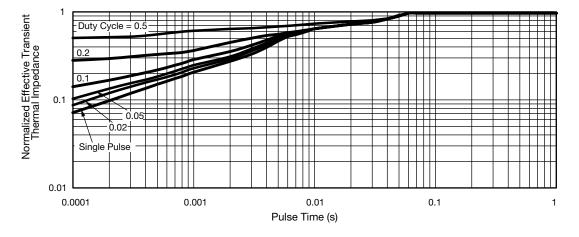


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



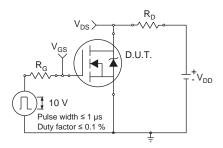


Fig. 12 - Switching Time Test Circuit

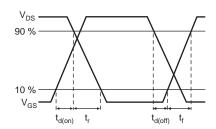


Fig. 13 - Switching Time Waveforms

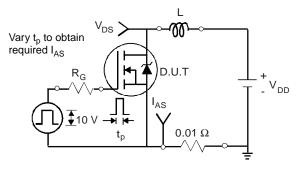


Fig. 14 - Unclamped Inductive Test Circuit

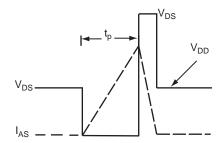


Fig. 15 - Unclamped Inductive Waveforms

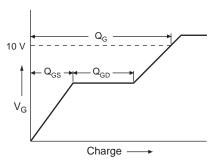


Fig. 16 - Basic Gate Charge Waveform

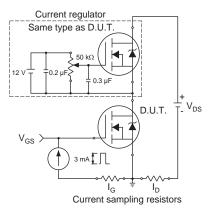
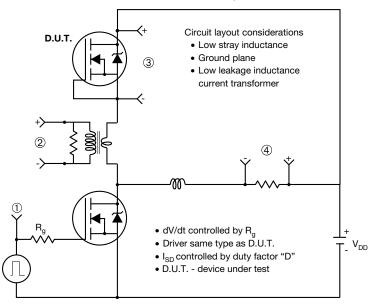


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



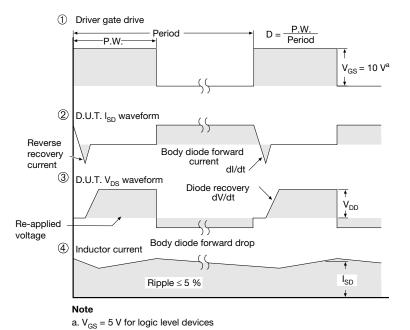
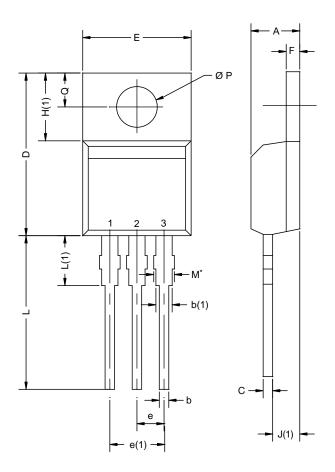


Fig. 18 - For N-Channel



TO-220AB



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
E	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØР	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12		

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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